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Atom Probe Field Ion Microscopy and Related Topics: A Bibliography 1989

M. K. Miller
A. R. Hawkins
K. F. Russell

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Metals and Ceramics Division

ATOM PROBE FIELD ION MICROSCOPY AND RELATED TOPICS: A BIBLIOGRAPHY 1989

M. K. Miller
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PREFACE

This bibliography includes references related to the following topics: atom probe field ion microscopy (APFIM), field ion microscopy (FIM), field emission microscopy (FEM), liquid metal ion sources (LMIS), scanning tunneling microscopy (STM), and theory. Technique-orientated studies and applications are included.

This bibliography covers the period 1989. Previous publications, *Atom Probe Field-ion Microscopy and Related Topics: A Bibliography 1978–1987*, complied by M. K. Miller and A. R. McDonald, ORNL/TM-11157, *Atom Probe Field-Ion Microscopy and Related Topics: A Bibliography 1988*, complied by M. K. Miller and A. R. Hawkins, ORNL/TM-11370, Oak Ridge National Laboratory, Oak Ridge, TN 37831-6285, and *Field-Ion Microscopy and Related Techniques, A Bibliography: 1951-1978*, compiled by R. E. Thurstans and J. M. Walls, published by Warwick, Birmingham, contains the papers published prior to this period.

The references contained in this document were compiled from a variety of sources including computer searches and personal lists of publications. To reduce the length of this document, the references have been reduced to the minimum necessary to locate the articles. The references are listed alphabetically by authors in the year in which they were published. This year differs from previous editions in that the publications are subdivided into the categories listed in paragraph one above.

We would like to thank Dr. G. D. W. Smith of Oxford University, Dr. J. Bentley of Oak Ridge National Laboratory (ORNL), and M. Alexander of the ORNL Central Library for their stoic efforts in the preparation of this document. We would also like to thank the many authors for supplying their personal publications lists and we apologize for any errors or omissions that may have occurred in compiling this document.

M. K. Miller, A. R. Hawkins, and K. F. Russell
Metals and Ceramics Division

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